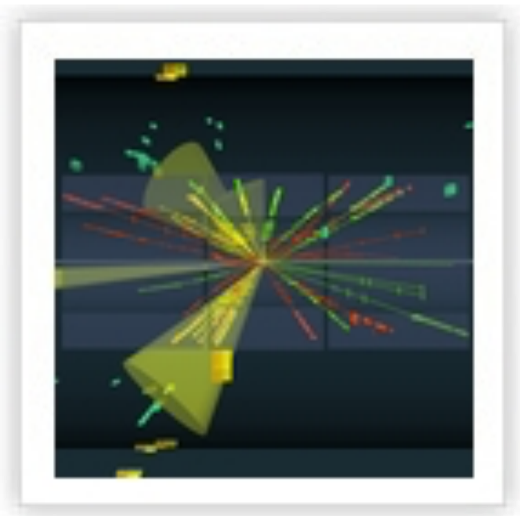
Statistical Methods for Particle Physics

Lecture 1: parameter estimation, statistical tests

http://benasque.org/2018tae/cgi-bin/talks/allprint.pl



CENTRO DE CIENCIAS DE BENASQUE PEDRO PASCUAL

TAE 2018
Benasque, Spain
3-15 Sept 2018

ROYAL HOLLOWAY UNIVERSITY OF LONDON

Glen Cowan
Physics Department
Royal Holloway, University of London
g.cowan@rhul.ac.uk
www.pp.rhul.ac.uk/~cowan

Outline

→ Lecture 1: Introduction and review of fundamentals

Probability, random variables, pdfs
Parameter estimation, maximum likelihood
Introduction to statistical tests

Lecture 2: More on statistical tests

Discovery, limits
Bayesian limits

Lecture 3: Framework for full analysis

Nuisance parameters and systematic uncertainties
Tests from profile likelihood ratio

Lecture 4: Further topics

More parameter estimation, Bayesian methods
Experimental sensitivity

Some statistics books, papers, etc.

G. Cowan, *Statistical Data Analysis*, Clarendon, Oxford, 1998

R.J. Barlow, *Statistics: A Guide to the Use of Statistical Methods in the Physical Sciences*, Wiley, 1989

Ilya Narsky and Frank C. Porter, *Statistical Analysis Techniques in Particle Physics*, Wiley, 2014.

L. Lyons, *Statistics for Nuclear and Particle Physics*, CUP, 1986

F. James., *Statistical and Computational Methods in Experimental Physics*, 2nd ed., World Scientific, 2006

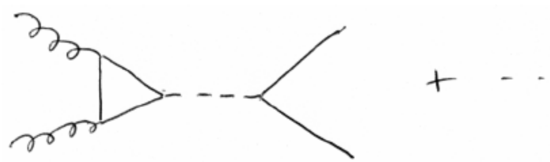
S. Brandt, *Statistical and Computational Methods in Data Analysis*, Springer, New York, 1998 (with program library on CD)

C. Patrignani et al. (Particle Data Group), *Review of Particle Physics*, Chin. Phys. C, 40, 100001 (2016); see also **`pdg.lbl.gov`** sections on probability, statistics, Monte Carlo

Theory ↔ Statistics ↔ Experiment

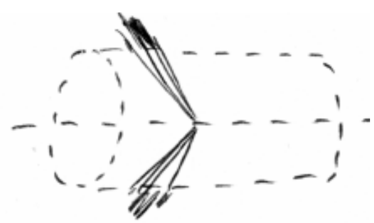
Theory (model, hypothesis):

$$\mathcal{L} = -\frac{1}{4} F_{\mu\nu} F^{\mu\nu} + i \bar{\psi} \not{D} \psi + \cdots$$

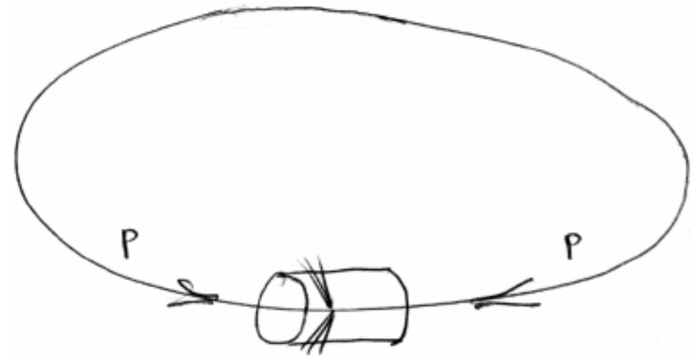


$$\sigma = \frac{G_F \, \alpha_s^2 \, m_H^2}{288 \sqrt{2\pi}} \times \sim$$

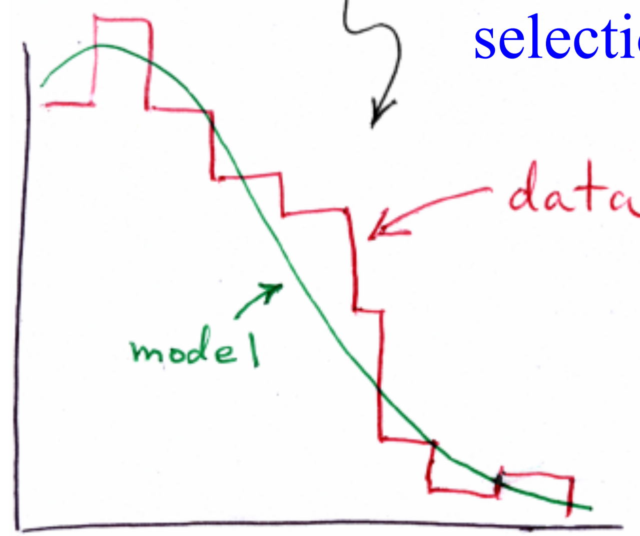
+ simulation of detector and cuts



Experiment:



+ data selection



Data analysis in particle physics

Observe events (e.g., pp collisions) and for each, measure a set of characteristics:

particle momenta, number of muons, energy of jets,...

Compare observed distributions of these characteristics to predictions of theory. From this, we want to:

Estimate the free parameters of the theory: $m_H = 125.4$

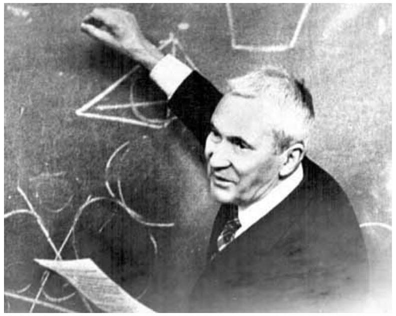
Quantify the uncertainty in the estimates: ± 0.4 GeV

Assess how well a given theory stands in agreement with the observed data: 0^+ good, 2^+ bad

To do this we need a clear definition of PROBABILITY

A definition of probability

Consider a set S with subsets A, B, ...



For all $A \subset S, P(A) \geq 0$

$$P(S) = 1$$

If $A \cap B = \emptyset, P(A \cup B) = P(A) + P(B)$

Kolmogorov axioms (1933)

Also define conditional probability of A given B:

$$P(A|B) = \frac{P(A \cap B)}{P(B)}$$

Subsets A, B independent if: $P(A \cap B) = P(A)P(B)$

If A, B independent, $P(A|B) = \frac{P(A)P(B)}{P(B)} = P(A)$

Interpretation of probability

I. Relative frequency

A, B, ... are outcomes of a repeatable experiment

$$P(A) = \lim_{n \to \infty} \frac{\text{times outcome is } A}{n}$$

cf. quantum mechanics, particle scattering, radioactive decay...

II. Subjective probability

A, B, ... are hypotheses (statements that are true or false)

$$P(A) = \text{degree of belief that } A \text{ is true}$$

- Both interpretations consistent with Kolmogorov axioms.
- In particle physics frequency interpretation often most useful, but subjective probability can provide more natural treatment of non-repeatable phenomena:

  systematic uncertainties, probability that Higgs boson exists,...

Bayes' theorem

From the definition of conditional probability we have,

$$P(A|B) = \frac{P(A \cap B)}{P(B)} \quad \text{and} \quad P(B|A) = \frac{P(B \cap A)}{P(A)}$$

but $P(A \cap B) = P(B \cap A)$, so

$$\boxed{P(A|B) = \frac{P(B|A)P(A)}{P(B)}}$$

Bayes' theorem

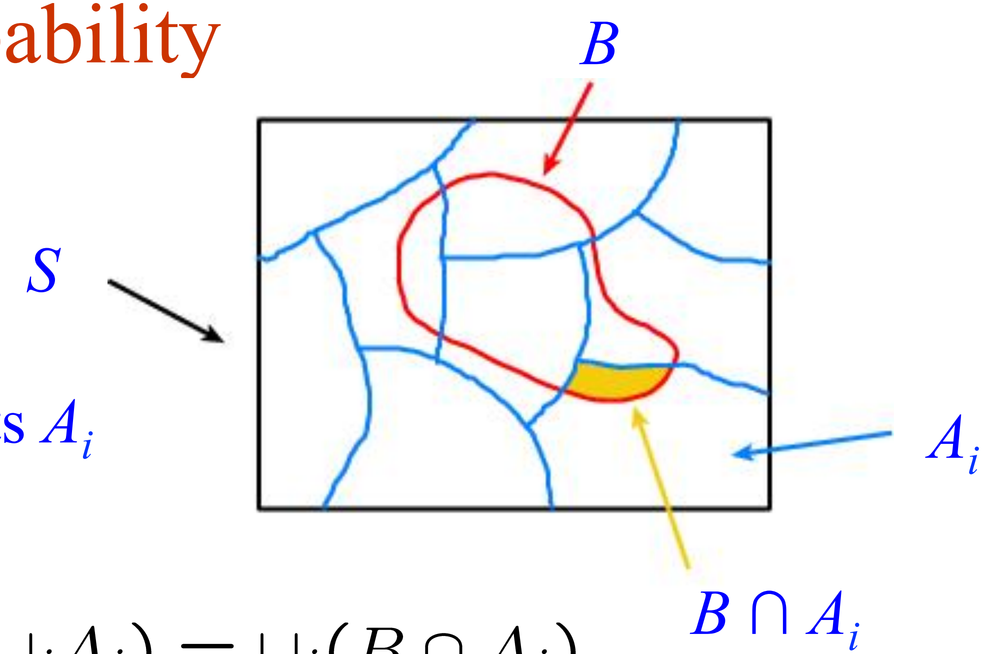
First published (posthumously) by the Reverend Thomas Bayes (1702−1761)

An essay towards solving a problem in the doctrine of chances, Philos. Trans. R. Soc. **53** (1763) 370; reprinted in Biometrika, **45** (1958) 293.

The law of total probability

Consider a subset B of the sample space S,

divided into disjoint subsets A_i such that $\cup_i A_i = S$,



$$\rightarrow \quad B = B \cap S = B \cap (\cup_i A_i) = \cup_i (B \cap A_i),$$

$$\rightarrow \quad P(B) = P(\cup_i (B \cap A_i)) = \sum_i P(B \cap A_i)$$

$$\rightarrow \quad P(B) = \sum_i P(B|A_i) P(A_i)$$ law of total probability

Bayes' theorem becomes

$$\boxed{P(A|B) = \frac{P(B|A)P(A)}{\sum_i P(B|A_i)P(A_i)}}$$

An example using Bayes' theorem

Suppose the probability (for anyone) to have a disease D is:

$$P(\mathrm{D}) = 0.001$$
$$P(\text{no D}) = 0.999$$

← prior probabilities, i.e., before any test carried out

Consider a test for the disease: result is + or −

$$P(+|\mathrm{D}) = 0.98$$
$$P(-|\mathrm{D}) = 0.02$$

← probabilities to (in)correctly identify a person with the disease

$$P(+|\text{no D}) = 0.03$$
$$P(-|\text{no D}) = 0.97$$

← probabilities to (in)correctly identify a healthy person

Suppose your result is +. How worried should you be?

Bayes' theorem example (cont.)

The probability to have the disease given a + result is

$$p(\mathrm{D}|+) = \frac{P(+|\mathrm{D})P(\mathrm{D})}{P(+|\mathrm{D})P(\mathrm{D}) + P(+|\text{no D})P(\text{no D})}$$

$$= \frac{0.98 \times 0.001}{0.98 \times 0.001 + 0.03 \times 0.999}$$

$$= 0.032$$ ← posterior probability

i.e. you're probably OK!

Your viewpoint: my degree of belief that I have the disease is 3.2%.

Your doctor's viewpoint: 3.2% of people like this have the disease.

Frequentist Statistics − general philosophy

In frequentist statistics, probabilities are associated only with the data, i.e., outcomes of repeatable observations (shorthand: $\vec{x}$).

Probability = limiting frequency

Probabilities such as

P (Higgs boson exists),
$P\,(0.117 < \alpha_s < 0.121)$,

etc. are either 0 or 1, but we don't know which.

The tools of frequentist statistics tell us what to expect, under the assumption of certain probabilities, about hypothetical repeated observations.

A hypothesis is is preferred if the data are found in a region of high predicted probability (i.e., where an alternative hypothesis predicts lower probability).

Bayesian Statistics − general philosophy

In Bayesian statistics, use subjective probability for hypotheses:

probability of the data assuming hypothesis H (the likelihood)

prior probability, i.e., before seeing the data

$$P(H|\vec{x}) = \frac{P(\vec{x}|H)\pi(H)}{\int P(\vec{x}|H)\pi(H)\,dH}$$

posterior probability, i.e., after seeing the data

normalization involves sum over all possible hypotheses

Bayes' theorem has an "if-then" character: If your prior probabilities were $\pi(H)$, then it says how these probabilities should change in the light of the data.

No general prescription for priors (subjective!)

The likelihood function

Suppose the entire result of an experiment (set of measurements) is a collection of numbers $\boldsymbol{x}$, and suppose the joint pdf for the data $\boldsymbol{x}$ is a function that depends on a set of parameters $\boldsymbol{\theta}$:

$$P(\mathbf{x}|\boldsymbol{\theta})$$

Now evaluate this function with the data obtained and regard it as a function of the parameter(s). This is the likelihood function:

$$\boxed{L(\boldsymbol{\theta}) = P(\mathbf{x}|\boldsymbol{\theta})}$$

($\boldsymbol{x}$ constant)

The likelihood function for i.i.d.*. data

* i.i.d. = independent and identically distributed

Consider n independent observations of x: $x_1, \ldots, x_n$, where x follows $f(x; \theta)$. The joint pdf for the whole data sample is:

$$f(x_1, \ldots, x_n; \theta) = \prod_{i=1}^{n} f(x_i; \theta)$$

In this case the likelihood function is

$$L(\vec{\theta}) = \prod_{i=1}^{n} f(x_i; \vec{\theta}) \qquad (x_i \text{ constant})$$

Frequentist parameter estimation

Suppose we have a pdf characterized by one or more parameters:

$$f(x;\theta) = \frac{1}{\theta} e^{-x/\theta}$$

random variable parameter

Suppose we have a sample of observed values: $\vec{x} = (x_1, \ldots, x_n)$

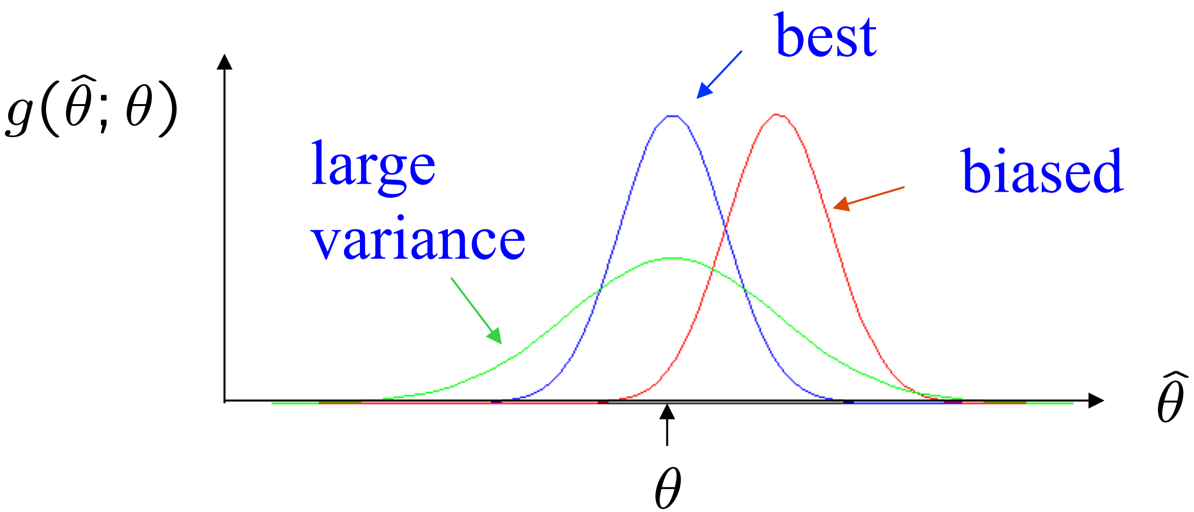
We want to find some function of the data to estimate the parameter(s):

$\boxed{\widehat{\theta}(\vec{x})}$ ← estimator written with a hat

Sometimes we say 'estimator' for the function of $x_1, \ldots, x_n$;
'estimate' for the value of the estimator with a particular data set.

Properties of estimators

Estimators are functions of the data and thus characterized by a sampling distribution with a given (co)variance:

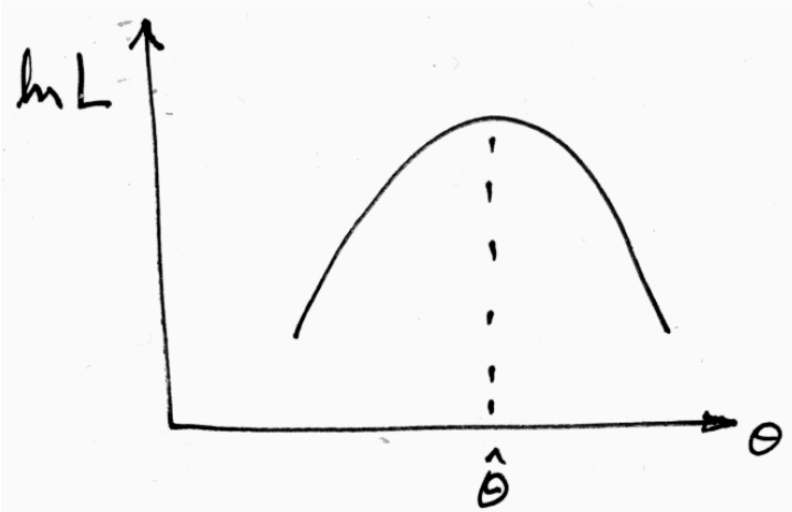


In general they may have a nonzero bias: $b = E[\hat{\theta}] - \theta$

Want small variance and small bias, but in general cannot optimize with respect to both; some trade-off necessary.

Maximum Likelihood (ML) estimators

The most important frequentist method for constructing estimators is to take the value of the parameter(s) that maximize the likelihood (or equivalently the log-likelihod):



$$\hat{\theta} = \underset{\theta}{\operatorname{argmax}} \, L(x|\theta)$$

In some cases we can find the ML estimator as a closed-form function of the data; more often it is found numerically.

ML example: parameter of exponential pdf

Consider exponential pdf, $f(t;\tau) = \frac{1}{\tau}e^{-t/\tau}$

and suppose we have i.i.d. data, $t_1, \ldots, t_n$

The likelihood function is $L(\tau) = \prod_{i=1}^{n} \frac{1}{\tau}e^{-t_i/\tau}$

The value of τ for which $L(\tau)$ is maximum also gives the maximum value of its logarithm (the log-likelihood function):

$$\ln L(\tau) = \sum_{i=1}^{n} \ln f(t_i;\tau) = \sum_{i=1}^{n} \left(\ln \frac{1}{\tau} - \frac{t_i}{\tau} \right)$$

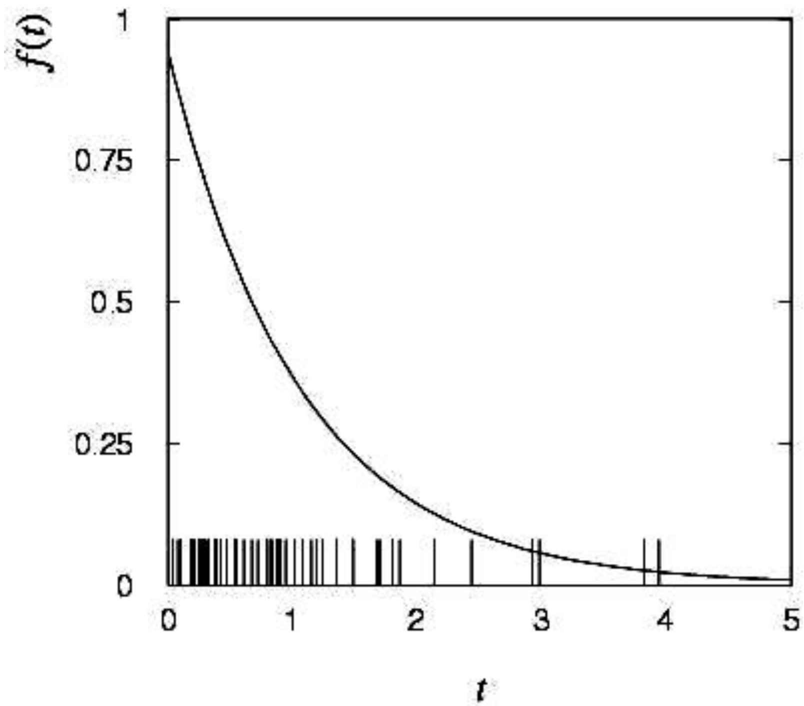
ML example: parameter of exponential pdf (2)

Find its maximum by setting $\dfrac{\partial \ln L(\tau)}{\partial \tau} = 0$,

$$\rightarrow \quad \widehat{\tau} = \frac{1}{n} \sum_{i=1}^{n} t_i$$

Monte Carlo test:

generate 50 values using $\tau = 1$:



We find the ML estimate:

$$\widehat{\tau} = 1.062$$

ML example: parameter of exponential pdf (3)

For the exponential distribution one has for mean, variance:

$$E[t] = \int_0^\infty t \, \frac{1}{\tau} e^{-t/\tau} \, dt = \tau$$

$$V[t] = \int_0^\infty (t-\tau)^2 \, \frac{1}{\tau} e^{-t/\tau} \, dt = \tau^2$$

For the ML estimator $\hat{\tau} = \frac{1}{n} \sum_{i=1}^{n} t_i$ we therefore find

$$E[\hat{\tau}] = E\left[\frac{1}{n}\sum_{i=1}^{n} t_i\right] = \frac{1}{n}\sum_{i=1}^{n} E[t_i] = \tau \quad \longrightarrow \quad b = E[\hat{\tau}] - \tau = 0$$

$$V[\hat{\tau}] = V\left[\frac{1}{n}\sum_{i=1}^{n} t_i\right] = \frac{1}{n^2}\sum_{i=1}^{n} V[t_i] = \frac{\tau^2}{n} \quad \longrightarrow \quad \sigma_{\hat{\tau}} = \frac{\tau}{\sqrt{n}}$$

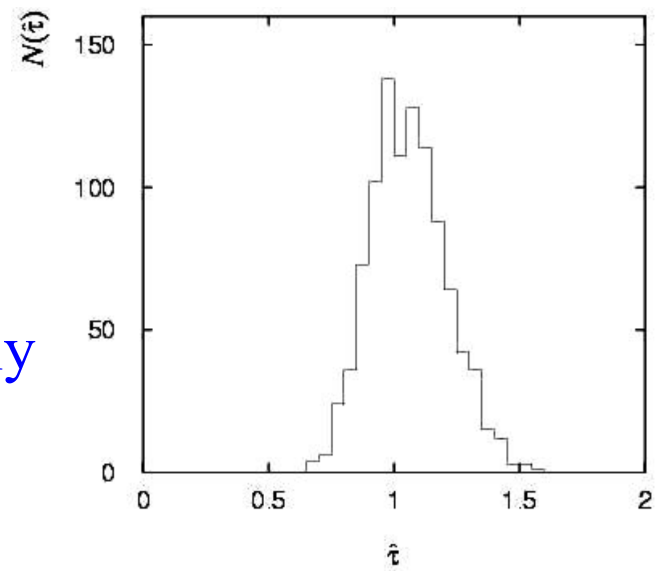
Variance of estimators: Monte Carlo method

Having estimated our parameter we now need to report its 'statistical error', i.e., how widely distributed would estimates be if we were to repeat the entire measurement many times.

One way to do this would be to simulate the entire experiment many times with a Monte Carlo program (use ML estimate for MC).

For exponential example, from sample variance of estimates we find:

$$\widehat{\sigma}_{\widehat{\tau}} = 0.151$$



Note distribution of estimates is roughly Gaussian − (almost) always true for ML in large sample limit.

Variance of estimators from information inequality

The information inequality (RCF) sets a lower bound on the variance of any estimator (not only ML):

Minimum Variance Bound (MVB)

$$V[\widehat{\theta}] \geq \left(1 + \frac{\partial b}{\partial \theta}\right)^2 \Big/ E\left[-\frac{\partial^2 \ln L}{\partial \theta^2}\right]$$

$$(b = E[\widehat{\theta}] - \theta)$$

Often the bias b is small, and equality either holds exactly or is a good approximation (e.g. large data sample limit). Then,

$$V[\widehat{\theta}] \approx -1 \Big/ E\left[\frac{\partial^2 \ln L}{\partial \theta^2}\right]$$

Estimate this using the 2nd derivative of $\ln L$ at its maximum:

$$\widehat{V}[\widehat{\theta}] = -\left(\frac{\partial^2 \ln L}{\partial \theta^2}\right)^{-1}\Bigg|_{\theta=\widehat{\theta}}$$

Variance of estimators: graphical method

Expand $\ln L(\theta)$ about its maximum:

$$\ln L(\theta) = \ln L(\hat{\theta}) + \left[\frac{\partial \ln L}{\partial \theta}\right]_{\theta=\hat{\theta}} (\theta - \hat{\theta}) + \frac{1}{2!}\left[\frac{\partial^2 \ln L}{\partial \theta^2}\right]_{\theta=\hat{\theta}} (\theta - \hat{\theta})^2 + \ldots$$

First term is $\ln L_{max}$, second term is zero, for third term use information inequality (assume equality):

$$\ln L(\theta) \approx \ln L_{\max} - \frac{(\theta - \hat{\theta})^2}{2\widehat{\sigma^2}_{\hat{\theta}}}$$

i.e., $$\ln L(\hat{\theta} \pm \hat{\sigma}_{\hat{\theta}}) \approx \ln L_{\max} - \frac{1}{2}$$

→ to get $\hat{\sigma}_{\hat{\theta}}$, change θ away from $\hat{\theta}$ until $\ln L$ decreases by 1/2.

Example of variance by graphical method

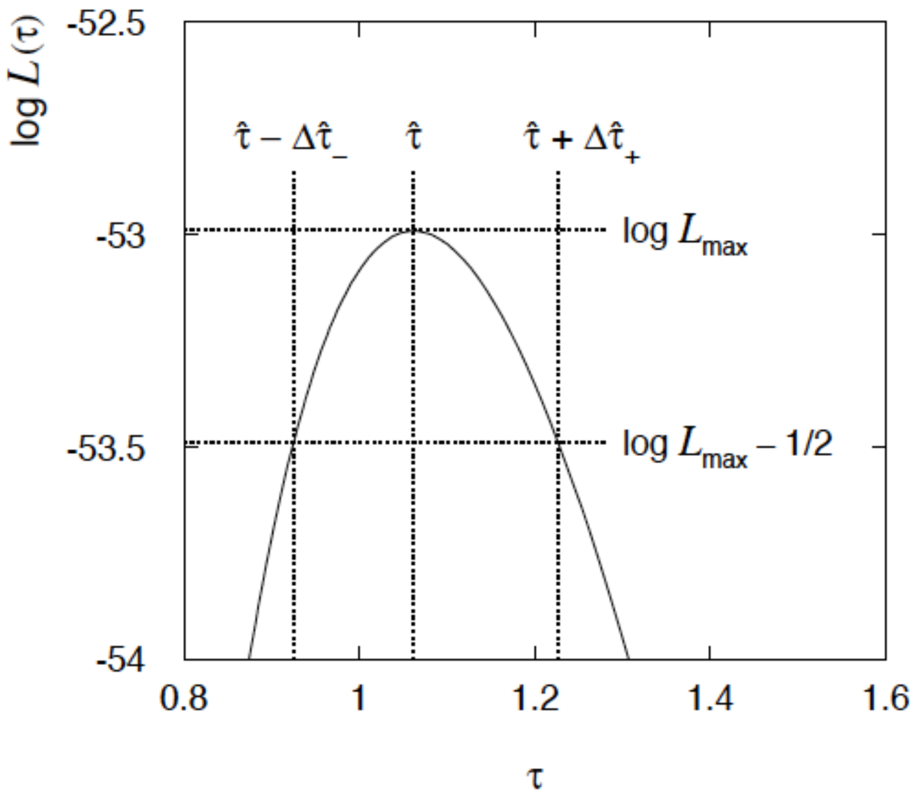
ML example with exponential:

$$\hat{\tau} = 1.062$$

$$\Delta\hat{\tau}_- = 0.137$$

$$\Delta\hat{\tau}_+ = 0.165$$

$$\hat{\sigma}_{\hat{\tau}} \approx \Delta\hat{\tau}_- \approx \Delta\hat{\tau}_+ \approx 0.15$$



Not quite parabolic ln L since finite sample size (n = 50).

Information inequality for N parameters

Suppose we have estimated N parameters $\vec{\theta} = (\theta_1, \ldots, \theta_N)$.

The (inverse) minimum variance bound is given by the Fisher information matrix:

$$I_{ij} = E\left[-\frac{\partial^2 \ln L}{\partial\theta_i \partial\theta_j}\right] = -n \int f(x;\vec{\theta}) \frac{\partial^2 \ln f(x;\vec{\theta})}{\partial\theta_i \partial\theta_j}\, dx$$

The information inequality then states that $V - I^{-1}$ is a positive semi-definite matrix, where $V_{ij} = \mathrm{cov}[\hat{\theta}_i, \hat{\theta}_j]$. Therefore

$$V[\hat{\theta}_i] \geq (I^{-1})_{ii}$$

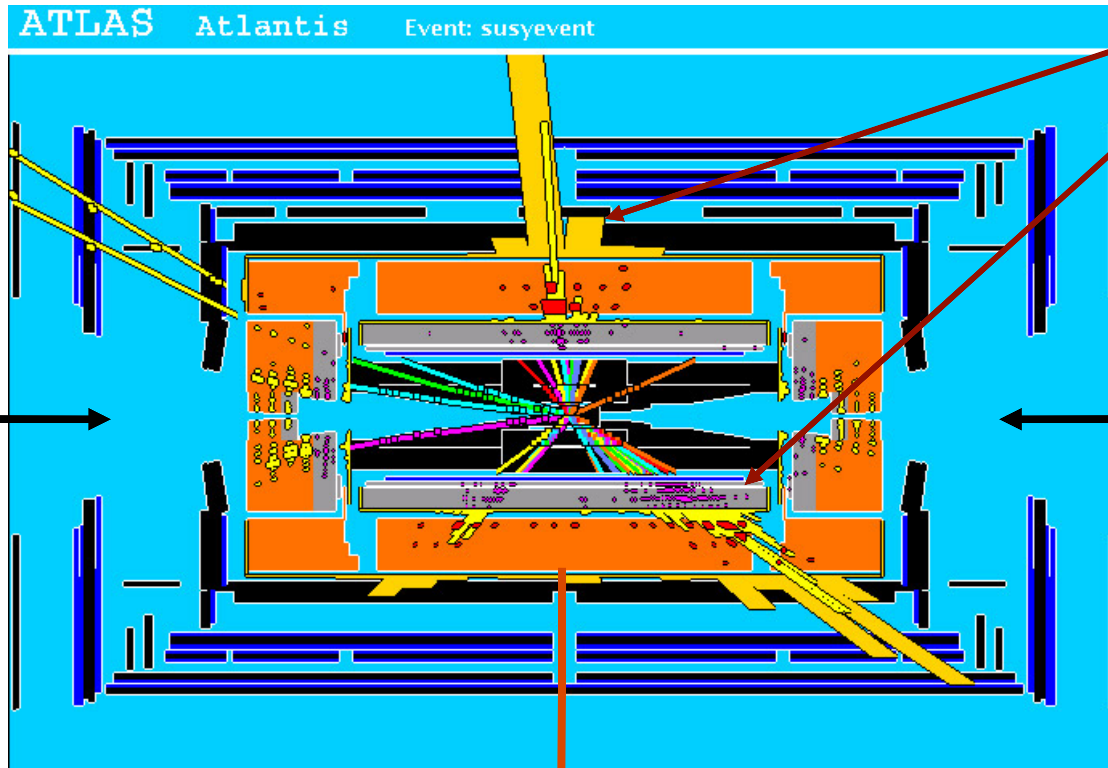
Often use I^{-1} as an approximation for covariance matrix, estimate using e.g. matrix of 2nd derivatives at maximum of L.

Prelude to statistical tests: A simulated SUSY event

high p_T muons

high p_T jets of hadrons

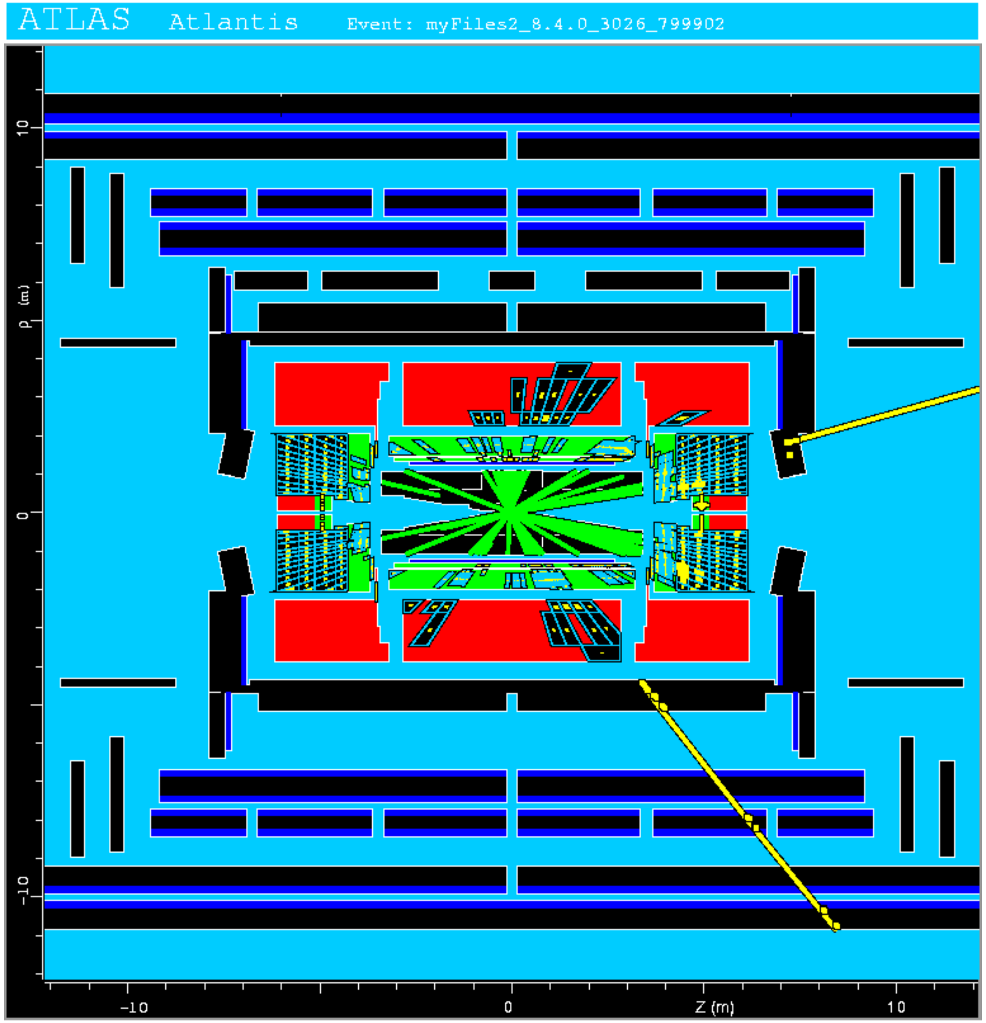
p



p

missing transverse energy

Background events



This event from Standard Model ttbar production also has high p_T jets and muons, and some missing transverse energy.

→ can easily mimic a SUSY event.

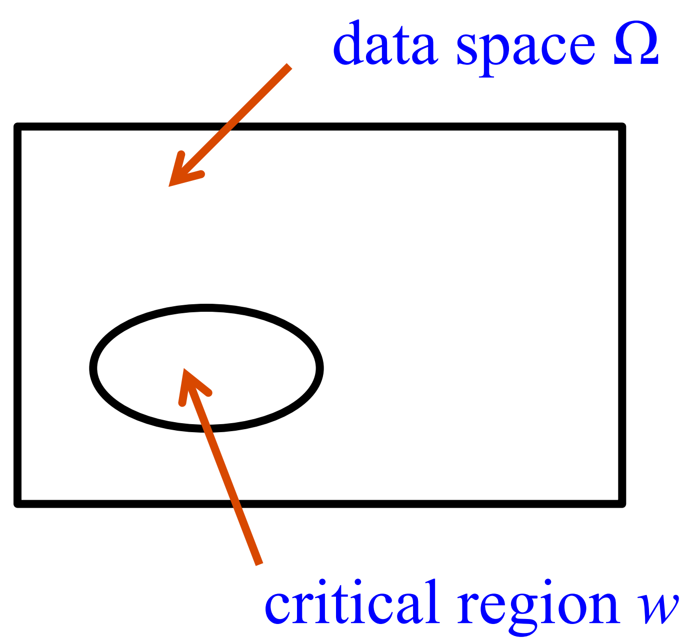
Frequentist statistical tests

Suppose a measurement produces data $\boldsymbol{x}$; consider a hypothesis H_0 we want to test and alternative H_1

H_0, H_1 specify probability for $\boldsymbol{x}$: $P(\boldsymbol{x}|H_0)$, $P(\boldsymbol{x}|H_1)$

A test of H_0 is defined by specifying a critical region w of the data space such that there is no more than some (small) probability α, assuming H_0 is correct, to observe the data there, i.e.,

$$P(x \in w \mid H_0) \leq \alpha$$



Need inequality if data are discrete.

α is called the size or significance level of the test.

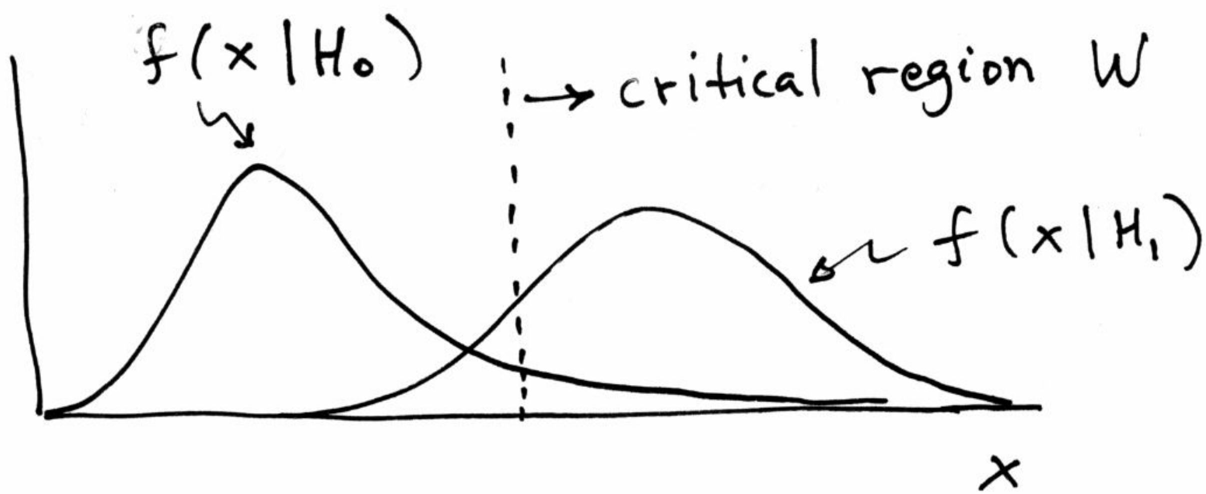
If x is observed in the critical region, reject H_0.

Definition of a test (2)

But in general there are an infinite number of possible critical regions that give the same significance level α.

So the choice of the critical region for a test of H_0 needs to take into account the alternative hypothesis H_1.

Roughly speaking, place the critical region where there is a low probability to be found if H_0 is true, but high if H_1 is true:



Classification viewed as a statistical test

Probability to reject H_0 if true (type I error): $$\alpha = \int_W f(\mathbf{x}|H_0)d\mathbf{x}$$

α = size of test, significance level, false discovery rate

Probability to accept H_0 if H_1 true (type II error) $$\beta = \int_{\overline{W}} f(\mathbf{x}|H_1)d\mathbf{x}$$

$1 - \beta$ = power of test with respect to H_1

Equivalently if e.g. H_0 = background, H_1 = signal, use efficiencies:

$$\varepsilon_{\mathrm{b}} = \int_W f(\mathbf{x}|H_0) = \alpha$$

$$\varepsilon_{\mathrm{s}} = \int_W f(\mathbf{x}|H_1) = 1 - \beta = \text{power}$$

Purity / misclassification rate

Consider the probability that an event of signal (s) type classified correctly (i.e., the event selection purity),

Use Bayes' theorem:

Here W is signal region

$$P(\mathrm{s}|\mathbf{x} \in W) = \frac{\overbrace{P(\mathbf{x} \in W|\mathrm{s})}^{\varepsilon_\mathrm{s}}\,\overbrace{P(\mathrm{s})}^{\text{prior probability}}}{P(\mathbf{x} \in W|\mathrm{s})P(\mathrm{s}) + \underbrace{P(\mathbf{x} \in W|\mathrm{b})}_{\varepsilon_\mathrm{b}}P(\mathrm{b})}$$

posterior probability = signal purity
= 1 – signal misclassification rate

Note purity depends on the prior probability for an event to be signal or background as well as on s/b efficiencies.

Physics context of a statistical test

Event Selection: data = individual event; goal is to classify

Example: separation of different particle types (electron vs muon) or known event types (ttbar vs QCD multijet).
E.g. test H_0 : event is background vs. H_1 : event is signal.
Use selected events for further study.

Search for New Physics: data = a sample of events. Test null hypothesis

H_0 : all events correspond to Standard Model (background only),

against the alternative

H_1 : events include a type whose existence is not yet established (signal plus background)

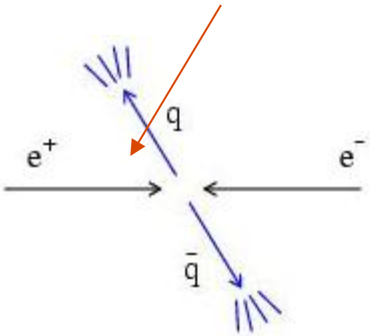
Many subtle issues here, mainly related to the high standard of proof required to establish presence of a new phenomenon. The optimal statistical test for a search is closely related to that used for event selection.

Extra slides

Example of ML with 2 parameters

Consider a scattering angle distribution with $x = \cos\,\theta$,

$$f(x;\alpha,\beta) = \frac{1 + \alpha x + \beta x^2}{2 + 2\beta/3}$$



or if $x_{\rm min} < x < x_{\rm max}$, need always to normalize so that

$$\int_{x_{\rm min}}^{x_{\rm max}} f(x;\alpha,\beta)\,dx = 1\;.$$

Example: $\alpha = 0.5$, $\beta = 0.5$, $x_{\rm min} = -0.95$, $x_{\rm max} = 0.95$, generate $n = 2000$ events with Monte Carlo.

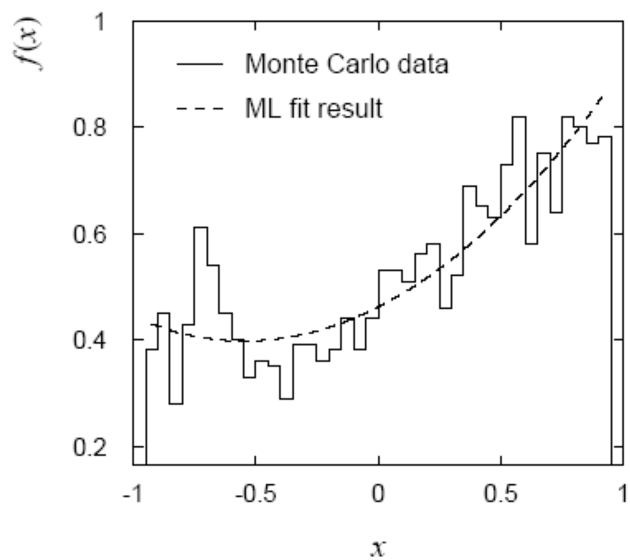
Example of ML with 2 parameters: fit result

Finding maximum of ln $L(\alpha, \beta)$ numerically (**MINUIT**) gives

$$\hat{\alpha} = 0.508$$

$$\hat{\beta} = 0.47$$

N.B. No binning of data for fit, but can compare to histogram for goodness-of-fit (e.g. 'visual' or χ^2).



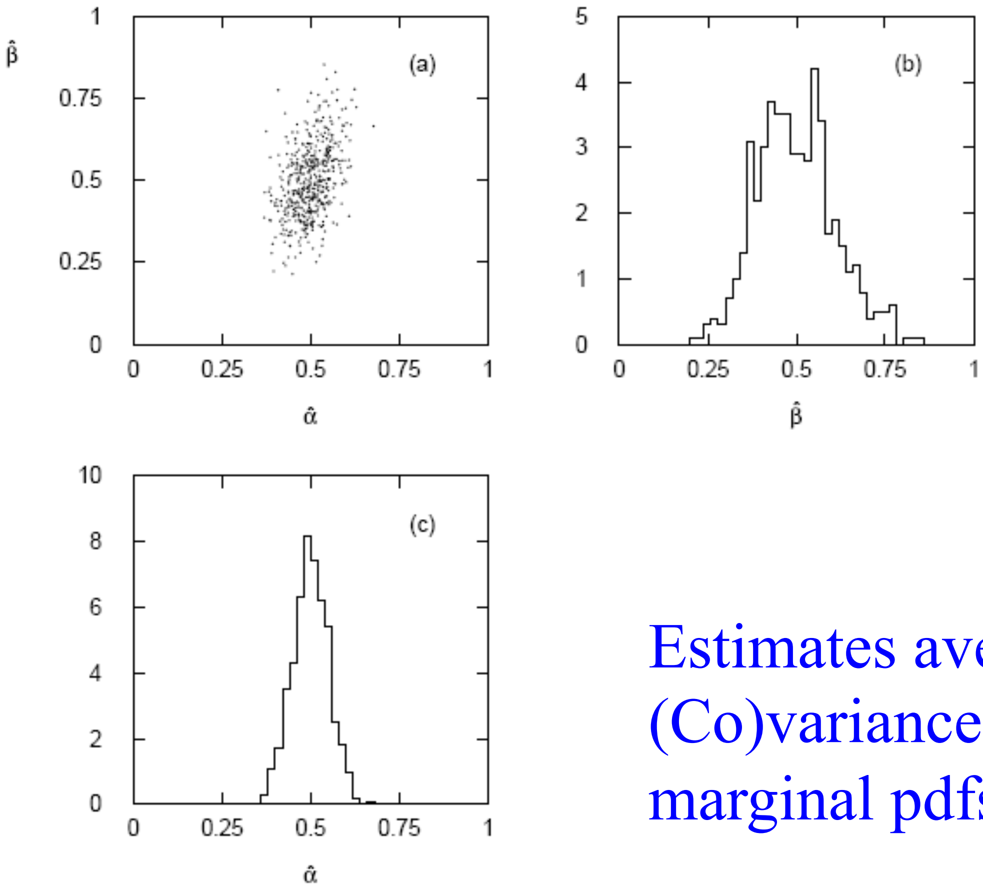
(Co)variances from $\widehat{(V^{-1})}_{ij} = - \left. \frac{\partial^2 \ln L}{\partial \theta_i \partial \theta_j} \right|_{\vec{\theta} = \hat{\vec{\theta}}}$ (**MINUIT** routine **HESSE**)

$$\hat{\sigma}_{\hat{\alpha}} = 0.052 \qquad \mathrm{cov}[\hat{\alpha}, \hat{\beta}] = 0.0026$$

$$\hat{\sigma}_{\hat{\beta}} = 0.11 \qquad r = 0.46$$

Two-parameter fit: MC study

Repeat ML fit with 500 experiments, all with $n = 2000$ events:



$$\overline{\hat{\alpha}} = 0.499$$
$$s_{\hat{\alpha}} = 0.051$$
$$\overline{\hat{\beta}} = 0.498$$
$$s_{\hat{\beta}} = 0.111$$
$$\widehat{\mathrm{cov}}[\hat{\alpha}, \hat{\beta}] = 0.0024$$
$$r = 0.42$$

Estimates average to ~ true values;
(Co)variances close to previous estimates;
marginal pdfs approximately Gaussian.

The ln $L_{\max}$ − 1/2 contour

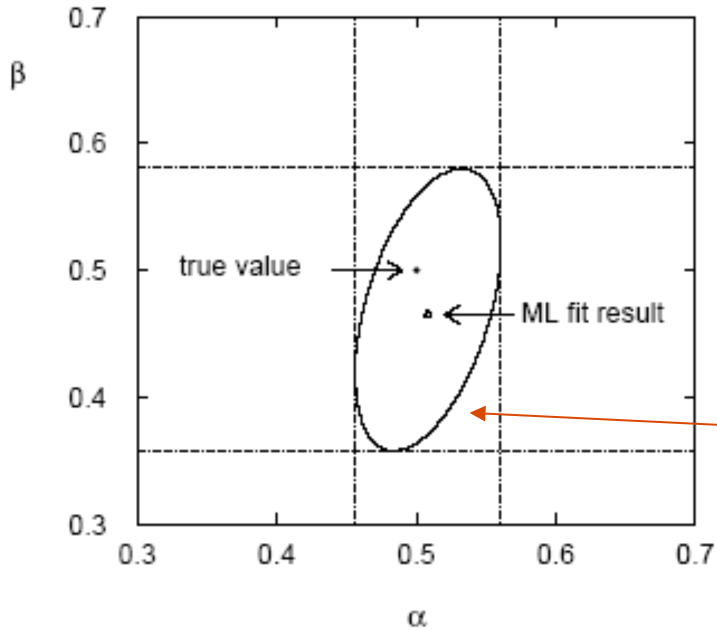
For large n, ln L takes on quadratic form near maximum:

$$\ln L(\alpha,\beta) \approx \ln L_{\max}$$
$$-\frac{1}{2(1-\rho^2)}\left[\left(\frac{\alpha-\hat{\alpha}}{\sigma_{\hat{\alpha}}}\right)^2 + \left(\frac{\beta-\hat{\beta}}{\sigma_{\hat{\beta}}}\right)^2 - 2\rho\left(\frac{\alpha-\hat{\alpha}}{\sigma_{\hat{\alpha}}}\right)\left(\frac{\beta-\hat{\beta}}{\sigma_{\hat{\beta}}}\right)\right]$$

The contour $\ln L(\alpha,\beta) = \ln L_{\max} - 1/2$ is an ellipse:

$$\frac{1}{(1-\rho^2)}\left[\left(\frac{\alpha-\hat{\alpha}}{\sigma_{\hat{\alpha}}}\right)^2 + \left(\frac{\beta-\hat{\beta}}{\sigma_{\hat{\beta}}}\right)^2 - 2\rho\left(\frac{\alpha-\hat{\alpha}}{\sigma_{\hat{\alpha}}}\right)\left(\frac{\beta-\hat{\beta}}{\sigma_{\hat{\beta}}}\right)\right] = 1$$

(Co)variances from ln *L* contour



The α, β plane for the first MC data set

$$\ln L(\alpha, \beta) = \ln L_{\max} - 1/2$$

→ Tangent lines to contours give standard deviations.

→ Angle of ellipse ϕ related to correlation: $\tan 2\phi = \dfrac{2\rho\sigma_{\hat{\alpha}}\sigma_{\hat{\beta}}}{\sigma^2_{\hat{\alpha}} - \sigma\hat{\beta}^2}$

Correlations between estimators result in an increase in their standard deviations (statistical errors).